

Citations for : **Dielectric Targets** Ion = **Xe**

Pub. Year	Authors, Title, Journal Citation and Comments	Citation Num
<b>1963</b>	McCargo, M. Davies, J. A. Brown, F. 'Range of Xe133 and Ar41 Ions of keV Energies in Tungsten' <i>Can. J. Phys.</i> , 41, 1231-44 (1963) <i>Comment</i> : R, dR. 2-200 keV 133Xe, 41Ar -> W, 40 keV 85Kr -> WO3	1963-McCa2
<b>1964</b>	Domeij, B. Mccargo, M. Davies, J. A. Brown, F. 'Ranges of Heavy Ions in Amorphous Oxides' <i>Bull. Am. Phys. Soc.</i> , 9, 109a (1964) <i>Comment</i> : R, dR. 5-160 keV Na, Kr, Xe -> Al2O3	1964-Dome3
<b>1966</b>	Whitton, J. L. Matzke, Hj. 'The Effect of Crystallinity and Bombardment Dose on the Penetration of 40 keV Xenon Ions in Ionic Crystals and Ceramics' <i>Can. J. Phys.</i> , 44, 2905-14 (1966) <i>Comment</i> : R, dR. 40 keV Xe -> NaCl, KBr, MgO, SiO2, UO2	1966-Whit
<b>1967</b>	Jespersgaard, P. Davies, J. A. 'Ranges of Na, K, W, and Xe Ions in Amorphous Al2O3 in the Energy Region 40-1000 keV' <i>Can. J. Phys.</i> , 45, 2983-94 (1967) <i>Comment</i> : R, dR. 40-1000 keV Na, K, Kr, Xe -> Al2O3	1967-Jesp
<b>1970</b>	Dearnaley, G. 'Ion Penetration' <i>European Conference on Ion Implantation, Reading, 162-171 (1970)</i> <i>Comment</i> : R. 10 keV-2 MeV Na, K, Kr, Xe, Ne -> Al2O3	1970-Dear
<b>1970</b>	Santry, D. C. Sitter, C. W. 'Range and Retention Studies of 40-keV Ions in Solids, in H' <i>Wagner, W. Walcher (Ed.) Proc. Int. Conf. Elmag. Isotope Separators and Their Techniques. Marburg, P. 505-24 (1970)</i> <i>Comment</i> : R, dR. 40 keV C, O, P, Co, Tl, Na, P, Co, Zn, Se, Kr, Hf, Cs, Ag, I, Xe -> Au, W, WO3	1970-Sant
<b>1970</b>	Schalch, D. Scharmann, A. 'Eindringtiefen von Ionen in CaF2-Und Rb-Aufdampfschichten' <i>Z. Angew. Phys.</i> , 29, 111-13 (1970) <i>Comment</i> : R. 10-80 keV H, He, Ne, Ar, Kr, Xe -> CaF2, Rb	1970-Scha
<b>1975</b>	Andersen, H. H. Bottiger, J. WolderJorgensen, H. 'Ranges of Ions with Z1 > 54 in Al and Al2O3' <i>Appl. Phys. Letters</i> , 26, 678-79 (1975) <i>Comment</i> : R, dR. (75-100 keV) Cs, Xe, Eu, Au, Tl -> Al, Al2O3	1975-Ande
<b>1976</b>	Pringle, J. P. S. 'A Comparison of Sectioning Methods used to Measure Concentration Profiles in Anodic Oxides' <i>Can. J. Phys.</i> , 54, 56-65 (1976) <i>Comment</i> : R, dR. (10-160 keV) Na, Ar, K, Kr, Xe -> Al2O3, Ta2O5, WO3, Ta2O5	1976-Prin

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<b>1980</b>	Bimbot, R. Gardes, D. Geissel, H. Kitahara, T. Armbuster, P. 'Stopping Power Measurements for 3-5 MeV/amu Kr, Xe, Pb and U in Solids' <i>Nucl. Inst. Methods, 174, 231-236 (1980)</i> <i>Comment : S. Kr, Xe, Pb, U (3-5 MeV/amu) -&gt; C, Al, Ti, Ni, Zr, Ag, Ta, Ir, Au, Mylar, Hostaphan</i>	1980-Bimb
<b>1988</b>	Balanzat, E. Jousset, J. C. Toulemonde, M. 'Latent Tracks Induced by Heavy Ions in the GeV Energy Range: Results at GANIL' <i>Nucl. Inst. Methods, B32, 368-376 (1988)</i> <i>Comment : R. O, Ar, Kr, Mo, Xe, U (4-85 MeV/amu) -&gt; Polymers, Insulators, Superconductors: Track Analysis</i>	1988-Bala
<b>1988</b>	Grande, P. L. Fichtner, P. F. P. Behar, M. Zawislak, F. C. 'Range Profiles of Medium and Heavy Ions Implanted into SiO2' <i>Nucl. Inst. Methods, B35, 17-20 (1988)</i> <i>Comment : R. As, Cs, Xe, Eu, Yb (10-200 keV) -&gt; SiO2</i>	1988-Gran
<b>1995</b>	Peterson, F. Enge, W. 'Energy Loss Dependent Transversal Etching Rates of Heavy Ion Tracks in Plastic' <i>Rad. Meas., 25, 43-46 (1995)</i> <i>Comment : S. Au, Xe (10-480 MeV/amu) -&gt; Makrofol</i>	1995-Pete
<b>1996</b>	Srivastava, A. Laldawngliana, C. Sinha, D. Ghosh, S. Dwivedi, K.K. 'Range and Energy Loss of Ni and Xe Ions in Hostaphan' <i>Indian J. Pure Appl. Phys., 34, 371-375 (1996)</i> <i>Comment : S,R. Ni, Xe -&gt; hostaphan</i>	1996-Sriv